

FORM: PTO-1449
(REV: 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEAtty Docket No:
94-0280.03

Serial No:

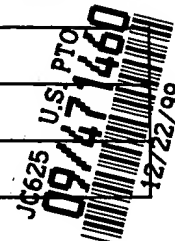
INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant:
Thomas A. Figura et al.Filing Date:
12/22/99

Group:

(37 CFR 1.98(b))

(use several sheets if necessary)



U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	
CL	AA 5,821,621	10/13/98	Jeng	257	759	
	AB 5,804,259	09/08/98	Robles	427	577	
	AC 5,496,773	03/05/96	Rhodes et al.	437	189	
	AD 5,486,493	01/23/96	Jeng	437	195	
	AE 5,476,817	12/19/95	Numata	437	195	
	AF 5,443,941	08/22/95	Bariya et al.	430	313	
	AG 5,422,310	06/06/95	Ito	437	192	
	AH 5,422,294	06/06/95	Noble, Jr.	437	52	
	AI 5,382,316	01/17/95	Hills et al.	156	643	
	AJ 5,364,817	11/15/94	Lur et al.	437	192	
	AK 5,364,809	11/15/94	Kwon et al.	437	52	
	AL 5,354,715	10/11/94	Wang et al.	437	238	
	AM 5,326,431	07/05/94	Kadomura	156	659.1	
	AN 5,312,773	05/17/94	Nagashima	437	190	
	AO 5,292,677	03/08/94	Dennison	437	52	
	AP 5,286,675	02/15/94	Chen et al.	437	195	
	AQ 5,284,787	02/08/94	Ahn	437	52	
	AR 5,232,509	08/03/93	Min et al.	118	723	
	AS 5,185,282	02/09/93	Lee et al.	437	47	
	AT 5,162,248	11/10/92	Dennison et al.	437	52	
	AU 5,150,276	09/22/92	Gonzalez et al.	361	313	
	AV 5,110,712	05/05/92	Kessler et al.	430	312	
	AW 5,096,849	03/17/92	Beilstein, Jr. et al.	437	67	
	AX 5,084,413	01/28/92	Fujita et al.	437	189	
	AY 5,066,607	11/19/91	Banerjee	437	52	
	AZ 4,918,033	04/17/90	Bartha et al.	437	245	
	BA 4,797,373	01/10/89	Malhi et al.	437	60	
CL	BB 4,759,958	07/26/88	Numata et al.	427	255.6	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes	No
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	BD					<input type="checkbox"/>	<input type="checkbox"/>

Initial

OTHER ART (including author, title, date, pertinent pages, etc.)

CL	BE	Tetsuo Ono, Ryoji Hamasaki and Tatsumi Mizutani, "Mechanism for CF Polymer Film Deposition through Deep Si ₂ Holes in Electron Cyclotron Resonance Plasma," Jpn. J. Appl. Phys. Vol. 35, pp. 2468-2471, Part 1, No. 4B, April 1996.
CL	BF	Ephrath, L. M., "Teflon Polymer Mask For RIE of Contact Roles," IBM Technical Disclosure Bulletin, Vol. 25, No. 9, pp. 4587-4588, February 1983.
Examiner: <i>Caroline</i>		Date Considered: 5.30.2000

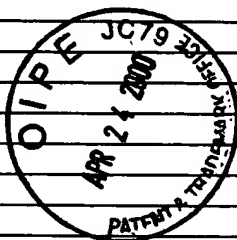
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FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 94-0280.03	Serial No: 09/471,460
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: Thomas A. Figura et al.	
		Filing Date: 12/22/99	Group: 2812

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	
<i>CL</i>	AA	5,904,799	05/18/99	Donohoe	156	345
<i>CL</i>	AB	5,837,596	11/17/98	Figura et al.	438	446
<i>CL</i>	AC	5,472,904	12/05/95	Figura et al.	437	67
	AD					
	AE					
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	AM					



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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes	No
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	AY					<input type="checkbox"/>	<input type="checkbox"/>

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OTHER ART (including author, title, date, pertinent pages, etc.)

	AZ		
	BA		
Examiner:	<i>caloula</i>		Date Considered: <i>5.30.2000</i>

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: Thomas A. Figura et al.	
		Filing Date: 12/22/99	Group: 2825

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass
CL	AA 5,562,801	10/08/96	Nulty	156	643.1
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	AC				
	AD				
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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
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	AY					<input type="checkbox"/>	<input type="checkbox"/>

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	AZ		
	BA		
Examiner:	<i>calvin</i>		Date Considered: <i>8.6.02</i>

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